| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|----------|----------|---------------------------------------|---|---------------------|---------|------------------|
| L1 | 46390 | ferroelectric · | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ÄDJ | ON | 2005/09/21 09:02 |
| L2 | 11290 | 1 same capacitor | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON . | 2005/09/21 09:02 |
| L3 | 4225 | (438/238,239,253,397).CCLS. | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | OR | OFF | 2005/09/21 09:03 |
| L4 | 579 | 3 and capacitor and 1 | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | ADJ | ON | 2005/09/21 09:34 |
| L5 | 519 | 2 and 3 | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | ADJ | ON | 2005/09/21 09:39 |
| L6 | 11259419 | @ad<"20000920" or @rlad<"20000920" | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | ADJ | ON | 2005/09/21 09:20 |
| L7 | 317 | 4 and 6 | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | ADJ | ON | 2005/09/21 09:33 |
| L8 | 2551 | (438/3,240).CCLS. | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | OR | OFF | 2005/09/21 09:34 |
| L9 | 1102 | 8 and capacitor and 1 | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | ADJ | ON | 2005/09/21 09:35 |
| L10 | 797 | 9 not 4 | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | ADJ | ON | 2005/09/21 09:37 |
| L11 | 413 | 10 and 6 | US-PGPUB; USPAT; EPO; JPO; IBM_TDB | ADJ | ON | 2005/09/21 09:39 |

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|-----|------|-------------------------------|---|-----|------|------------------|
| L12 | 519 | 2 and 3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 09:40 |
| L13 | 0 | 5 not 4 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 09:40 |
| L14 | 1 | dummey electrode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 09:43 |
| L15 | 3 | dummey with electrode | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON . | 2005/09/21 09:45 |
| L16 | 2058 | 2 and (second adj2 electrode) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 09:46 |
| L17 | 6094 | 3 or 8 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 09:46 |
| L18 | 424 | 16 and 17 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 09:46 |
| L19 | 231 | 18 and 6 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 09:47 |
| L20 | 119 | 19 not 4 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 10:42 |
| L21 | 64 | Chain FRAM | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2005/09/21 10:43 |



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| IEE CNF IEE Conference Proceeding | | | Digital Object Identifier 10.1109/4.799863 | | | | |
| IEEE STD | IEEE Standard | | Abstract Full Text: PDF(340 KB) IEEE JNL | | | | |
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